

Notice of References Cited

 Application/Control No.
 10/040,433

 Applicant(s)/Patent Under
 Reexamination
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,190,803	02-2001	Tomiyama et al.	429/245
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
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FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

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